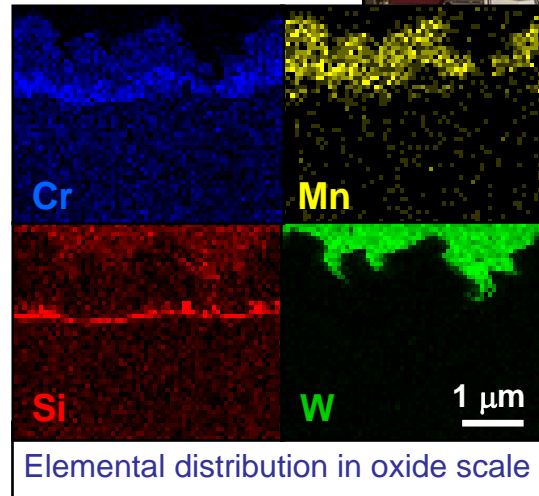
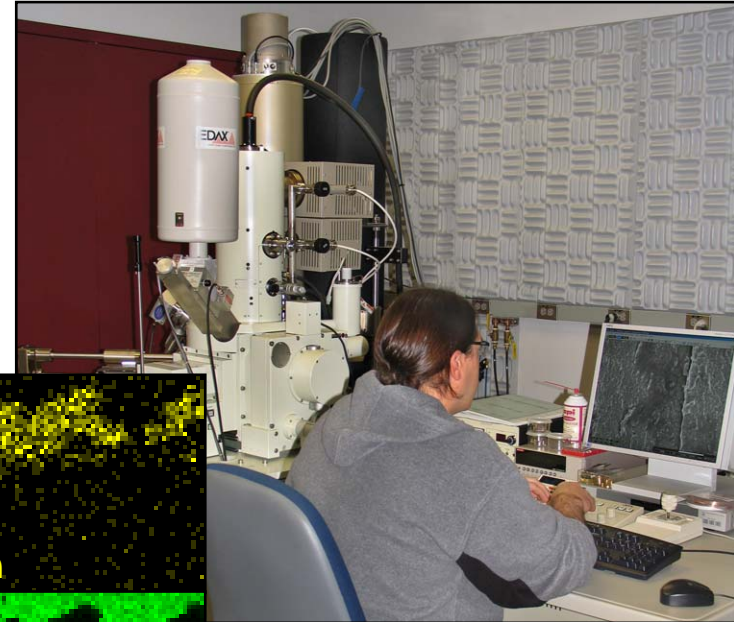


# JEOL 6500F SEM

## Techniques/Capabilities:

- High current, 30kV FE gun
- Secondary/BS electron imaging down to 0.5 and 1kV, respectively
- Si drift and microcalorimeter EDS X-ray detectors ( $Z>3$ )
- High speed / high spectral resolution EDS spectrum imaging
- Dry pumping system/in-situ plasma cleaning of specimens
- High speed beam blanking and insertable Faraday cup



## Current Research Activities:

- Structural characterization of high temperature alloys, composites, ceramics, nano-structured materials, environmental effects (oxidation, transformation)
- Low voltage operation to provide higher spatial resolution EDS analysis/mapping
- Elemental/phase distribution via EDS analysis/mapping, BSE imaging (above)

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